

100V N-SGT Enhancement Mode MOSFET

General Description

APG12N10D use advanced SGT MOSFET technology to provide low RDS(ON), low gate charge, fast switching and excellent avalanche characteristics.

This device is specially designed to get better ruggedness and suitable to use in

Features

Low RDS(on) & FOM

Extremely low switching loss

Excellent stability and uniformity or Invertors

Applications

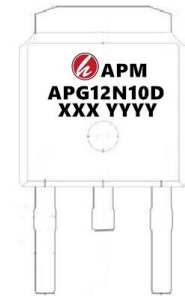
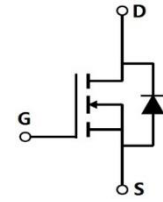
Consumer electronic power supply

Motor control

Synchronous-rectification

Isolated DC

Synchronous-rectification applications



Package Marking and Ordering Information

| Product ID | Pack | Marking | Qty(PCS) |
|------------|--------|--------------------|----------|
| APG12N10D | TO-252 | APG12N10D XXX YYYY | 2500 |

Absolute Maximum Ratings at $T_j=25^\circ\text{C}$ unless otherwise noted

| Parameter | Symbol | Value | Unit |
|---|-----------------------------------|------------|--------------------|
| Drain source voltage | VDS | 100 | V |
| Gate source voltage | VGS | ± 20 | V |
| Continuous drain current ¹⁾ , $T_c=25^\circ\text{C}$ | I _D | 12 | A |
| Pulsed drain current ²⁾ , $T_c=25^\circ\text{C}$ | I _D , pulse | 24 | A |
| Power dissipation ³⁾ , $T_c=25^\circ\text{C}$ | P _D | 17 | W |
| Single pulsed avalanche energy ⁵⁾ | EAS | 1.2 | mJ |
| Operation and storage temperature | T _{stg} , T _j | -55 to 150 | $^\circ\text{C}$ |
| Thermal resistance, junction-case | R θ JC | 7.4 | $^\circ\text{C/W}$ |
| Thermal resistance, junction-ambient ⁴⁾ | R θ JA | 62 | $^\circ\text{C/W}$ |

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Electrical Characteristics at $T_j=25\text{ }^\circ\text{C}$ unless otherwise specified

| Symbol | Parameter | Test condition | Min. | Typ. | Max. | Unit | |
|---------------|----------------------------------|--|------------------------|-------|------|---------------|----|
| BV_{DSS} | Drain-source breakdown voltage | $V_{GS}=0\text{ V}, I_D=250\text{ }\mu\text{A}$ | 100 | 111 | | V | |
| $V_{GS(th)}$ | Gate threshold voltage | $V_{DS}=V_{GS}, I_D=250\text{ }\mu\text{A}$ | 1.2 | 2.0 | 2.5 | V | |
| $R_{DS(ON)}$ | Drain-source on-state resistance | $V_{GS}=10\text{ V}, I_D=5\text{ A}$ | | 105 | 125 | m Ω | |
| $R_{DS(ON)}$ | Drain-source on-state resistance | $V_{GS}=4.5\text{ V}, I_D=3\text{ A}$ | | 115 | 145 | m Ω | |
| I_{GSS} | Gate-source leakage current | $V_{GS}=20\text{ V}$ | | | 100 | nA | |
| | | $V_{GS}=-20\text{ V}$ | | | -100 | | |
| I_{DSS} | Drain-source leakage current | $V_{DS}=100\text{ V}, V_{GS}=0\text{ V}$ | | | 1 | μA | |
| C_{iss} | Input capacitance | $V_{GS}=0\text{ V},$ $V_{DS}=50\text{ V},$ $f=100\text{ kHz}$ | | 206.1 | | pF | |
| C_{oss} | Output capacitance | | | 28.9 | | pF | |
| C_{rss} | Reverse transfer capacitance | | | 1.4 | | pF | |
| $t_{d(on)}$ | Turn-on delay time | | | 14.7 | | ns | |
| t_r | Rise time | $V_{GS}=10\text{ V},$ $V_{DS}=50\text{ V},$ $R_G=2\text{ }\Omega,$ $I_D=5\text{ A}$ | | 3.5 | | ns | |
| $t_{d(off)}$ | Turn-off delay time | | | 20.9 | | ns | |
| t_f | Fall time | | | 2.7 | | ns | |
| Q_g | Total gate charge | | | 4.3 | | nC | |
| Q_{gs} | Gate-source charge | $I_D=5\text{ A},$ $V_{DS}=50\text{ V},$ $V_{GS}=10\text{ V}$ | | 1.5 | | nC | |
| Q_{gd} | Gate-drain charge | | | 1.1 | | nC | |
| $V_{plateau}$ | Gate plateau voltage | | | 5.0 | | V | |
| I_S | Diode forward current | | | | | 7 | A |
| I_{SP} | Pulsed source current | $V_{GS}<V_{th}$ | | | 21 | | |
| V_{SD} | Diode forward voltage | $I_S=7\text{ A}, V_{GS}=0\text{ V}$ | | | 1.0 | V | |
| t_{rr} | Reverse recovery time | $I_S=5\text{ A}, di/dt=100$ | | 32.1 | | ns | |
| Q_{rr} | Reverse recovery charge | | | | 39.4 | | nC |
| I_{rrm} | Peak reverse recovery current | | $\text{A}/\mu\text{s}$ | | 2.1 | | A |

Note

- 1) Calculated continuous current based on maximum allowable junction temperature.
- 2) Repetitive rating; pulse width limited by max. junction temperature.
- 3) P_d is based on max. junction temperature, using junction-case thermal resistance.
- 4) The value of $R_{\theta JA}$ is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with $T_a=25\text{ }^\circ\text{C}$.
- 5) $V_{DD}=50\text{ V}, R_G=50\text{ }\Omega, L=0.3\text{ mH}$, starting $T_j=25\text{ }^\circ\text{C}$.

Electrical Characteristics Diagrams

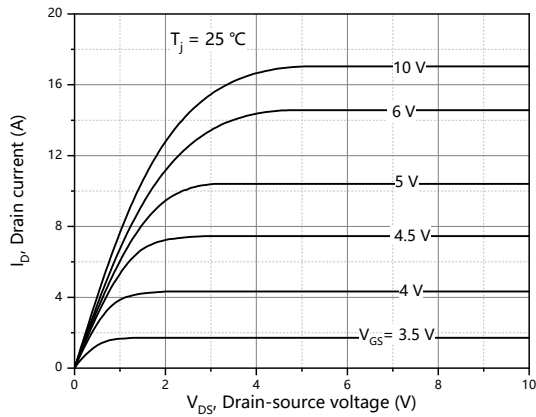


Figure 1, Typ. output characteristics

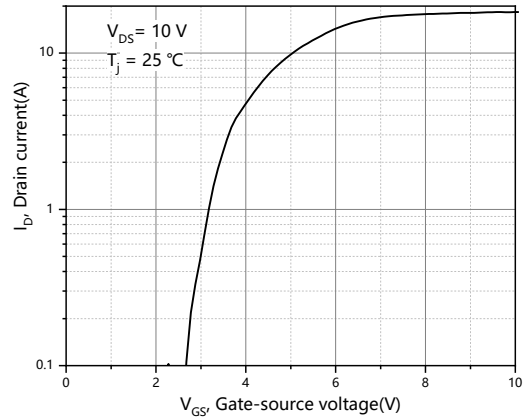


Figure 2, Typ. transfer characteristics

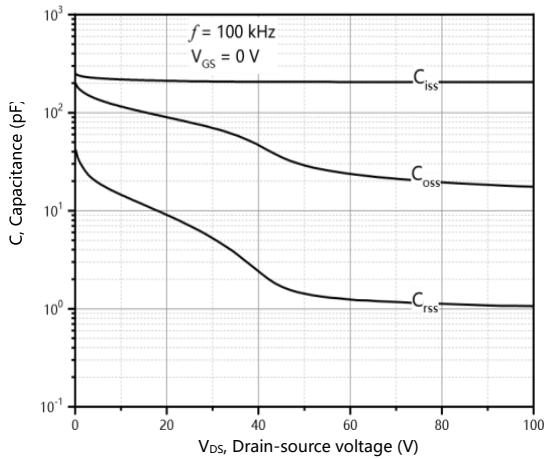


Figure 3, Typ. capacitances

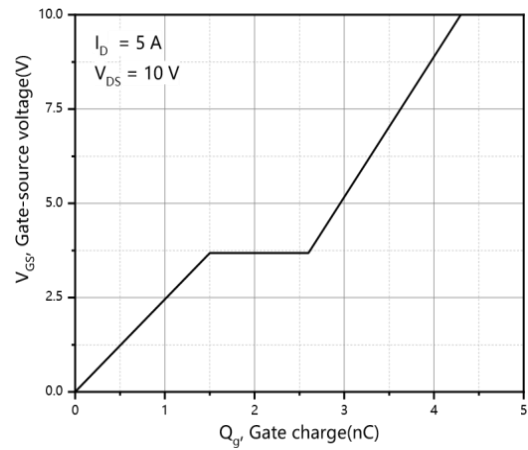


Figure 4, Typ. gate charge

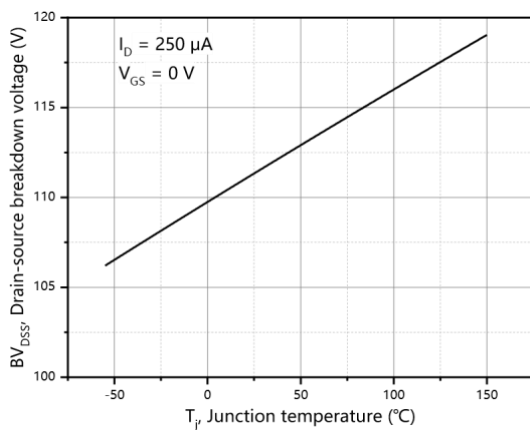


Figure 5, Drain-source breakdown voltage

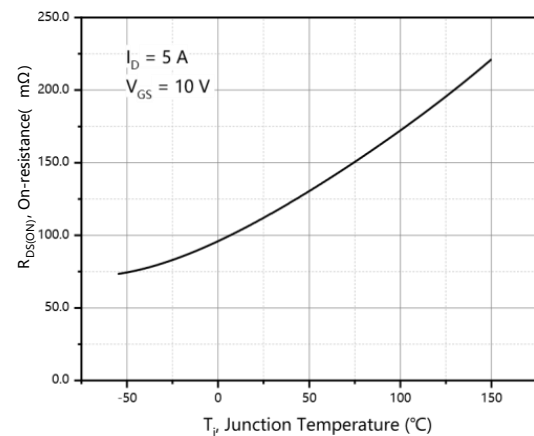


Figure 6, Drain-source on-state resistance

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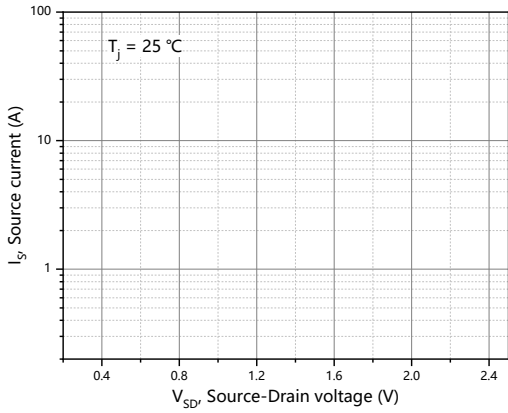


Figure 7, Forward characteristic of body diode

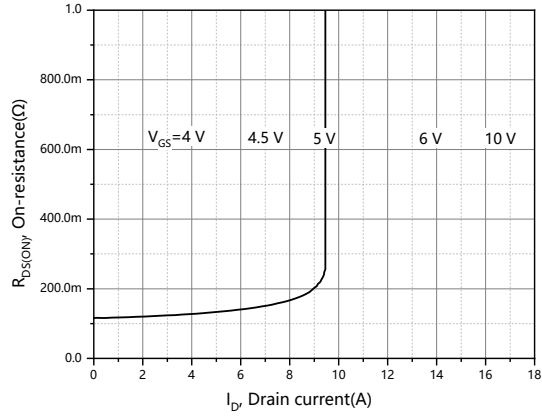


Figure 8, Drain-source on-state resistance

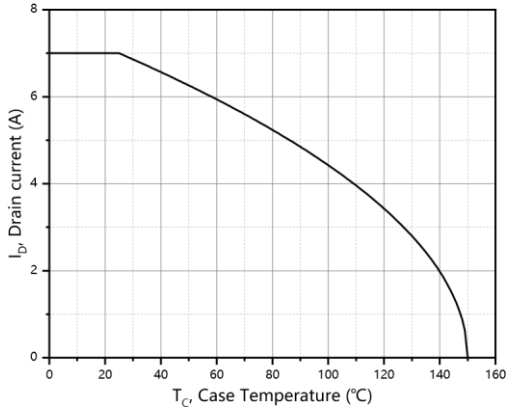


Figure 9, Drain current

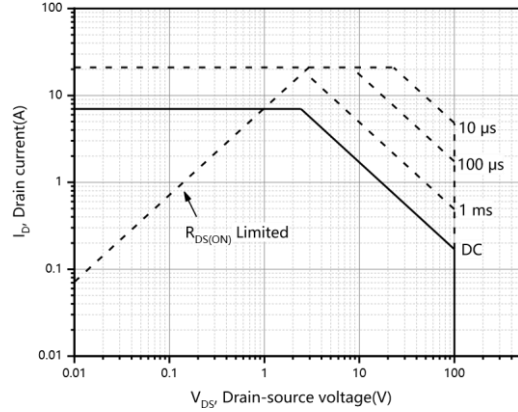


Figure 10, Safe operation area $T_C=25\text{ }^\circ\text{C}$

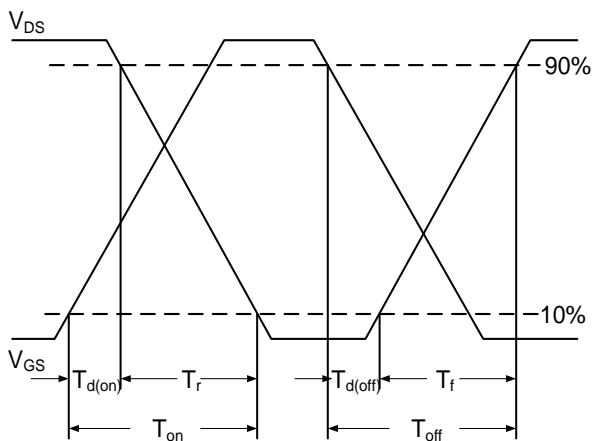


Fig.11 Switching Time Waveform

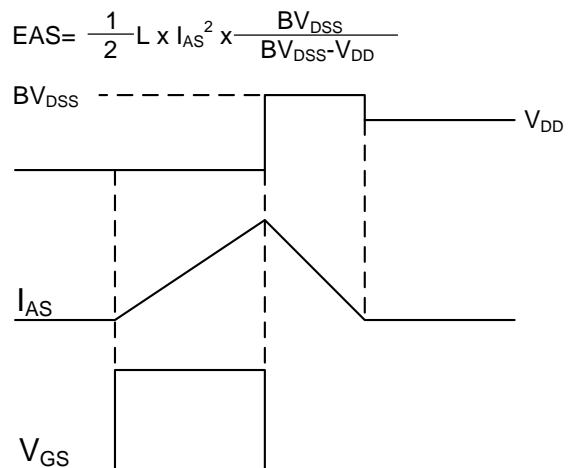
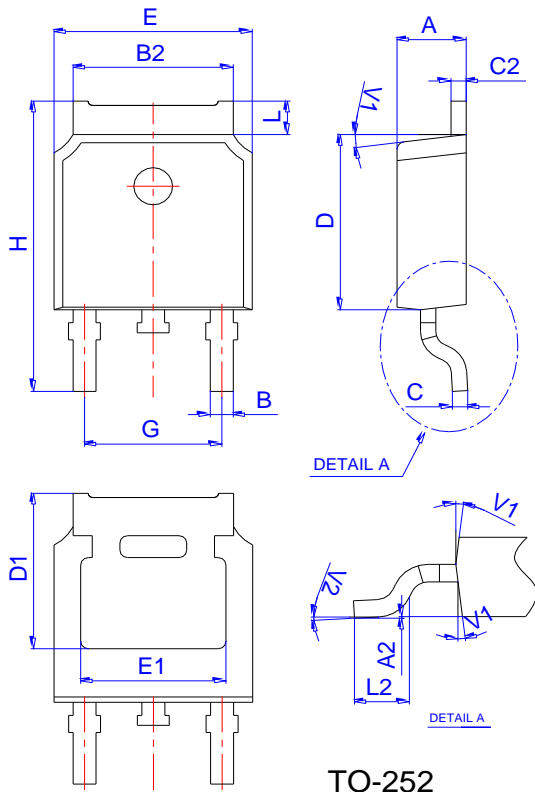


Fig.12 Unclamped Inductive Switching Waveform

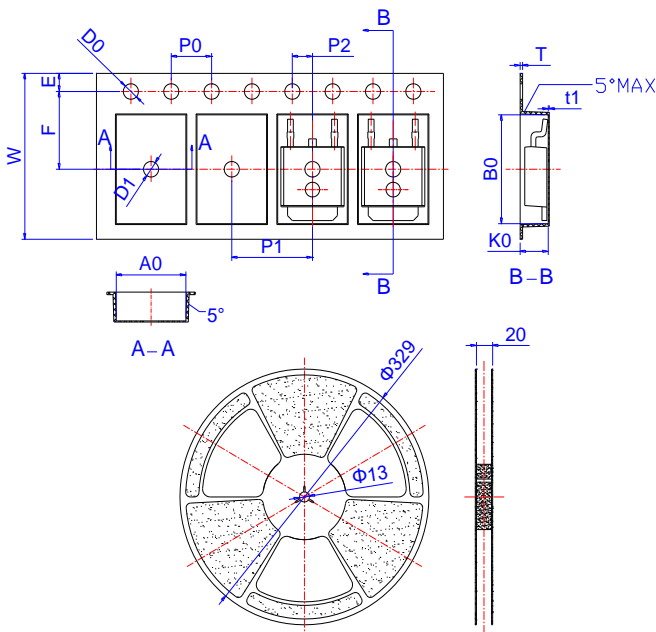
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Package Mechanical Data-TO-252-3L



| Ref. | Dimensions | | | | | |
|------|-------------|------|-------|----------|------|-------|
| | Millimeters | | | Inches | | |
| | Min. | Typ. | Max. | Min. | Typ. | Max. |
| A | 2.10 | | 2.50 | 0.083 | | 0.098 |
| A2 | 0 | | 0.10 | 0 | | 0.004 |
| B | 0.66 | | 0.86 | 0.026 | | 0.034 |
| B2 | 5.18 | | 5.48 | 0.202 | | 0.216 |
| C | 0.40 | | 0.60 | 0.016 | | 0.024 |
| C2 | 0.44 | | 0.58 | 0.017 | | 0.023 |
| D | 5.90 | | 6.30 | 0.232 | | 0.248 |
| D1 | 5.30REF | | | 0.209REF | | |
| E | 6.40 | | 6.80 | 0.252 | | 0.268 |
| E1 | 4.63 | | | 0.182 | | |
| G | 4.47 | | 4.67 | 0.176 | | 0.184 |
| H | 9.50 | | 10.70 | 0.374 | | 0.421 |
| L | 1.09 | | 1.21 | 0.043 | | 0.048 |
| L2 | 1.35 | | 1.65 | 0.053 | | 0.065 |
| V1 | | 7° | | | 7° | |
| V2 | 0° | | 6° | 0° | | 6° |

Reel Specification-TO-252



| Ref. | Dimensions | | | | | |
|------|-------------|-------|-------|--------|-------|-------|
| | Millimeters | | | Inches | | |
| | Min. | Typ. | Max. | Min. | Typ. | Max. |
| W | 15.90 | 16.00 | 16.10 | 0.626 | 0.630 | 0.634 |
| E | 1.65 | 1.75 | 1.85 | 0.065 | 0.069 | 0.073 |
| F | 7.40 | 7.50 | 7.60 | 0.291 | 0.295 | 0.299 |
| D0 | 1.40 | 1.50 | 1.60 | 0.055 | 0.059 | 0.063 |
| D1 | 1.40 | 1.50 | 1.60 | 0.055 | 0.059 | 0.063 |
| P0 | 3.90 | 4.00 | 4.10 | 0.154 | 0.157 | 0.161 |
| P1 | 7.90 | 8.00 | 8.10 | 0.311 | 0.315 | 0.319 |
| P2 | 1.90 | 2.00 | 2.10 | 0.075 | 0.079 | 0.083 |
| A0 | 6.85 | 6.90 | 7.00 | 0.270 | 0.271 | 0.276 |
| B0 | 10.45 | 10.50 | 10.60 | 0.411 | 0.413 | 0.417 |
| K0 | 2.68 | 2.78 | 2.88 | 0.105 | 0.109 | 0.113 |
| T | 0.24 | | 0.27 | 0.009 | | 0.011 |
| t1 | 0.10 | | | 0.004 | | |
| 10P0 | 39.80 | 40.00 | 40.20 | 1.567 | 1.575 | 1.583 |

100V N-SGT Enhancement Mode MOSFET**Attention**

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APG12N10D

100V N-SGT Enhancement Mode MOSFET

| Edition | Date | Change |
|---------|-----------|----------------------|
| Rve1.0 | 2019/1/31 | Initial release |
| Rve1.1 | 2019/8/15 | Reducing VTH To 1.5V |

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